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Application/Control No.	Applicant(s)/Patent unde Reexamination	r
10/811,853	KIM ET AL.	
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Jason Heckert	1746	

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SEARCH (INCLUDING SEA		ίΥ) <u>·</u> _
	DATE	EXMR
Updated Search	8/14/2007	JMH
Consulted M. Barr	8/14/2007	JMH
Consulted J. Perrin	8/14/2007	JMH
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